


<b>Search Notes</b>  	<b>Application/Control No.</b>  10507066	<b>Applicant(s)/Patent Under Reexamination</b>  YE, SHEN
	<b>Examiner</b>  Benny Lee	<b>Art Unit</b>  2817

SEARCHED			
Class	Subclass	Date	Examiner
333	99S, 204, 219	23 January 2008	BTL
505	210, 866	25 January 2008	BTL

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner